

Search Notes



Application/Control No.

09/764,787

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

SCHWARTZ ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	3/06	DN
	7		
	8		
	10		
	26		
709	206		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	3/06	DN
Patent PG Pub		
II FOREIGN	3/06	
1. EPO		
2. JPO		
3. Derwent		
4. IBM-TDB		